

MC request for new AFB-q(off Z-pole) study at high energy

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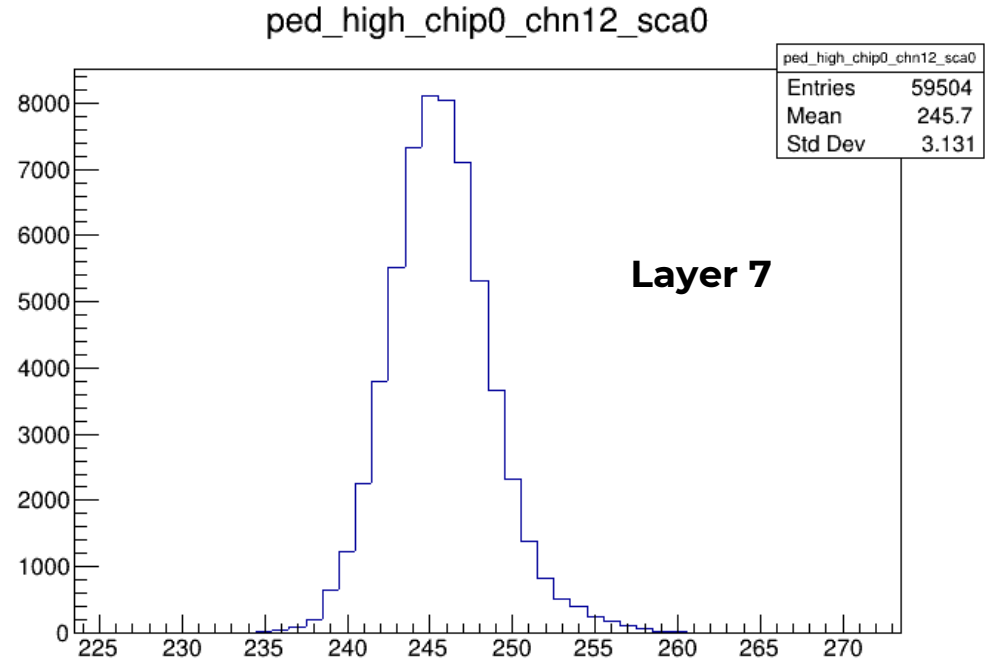
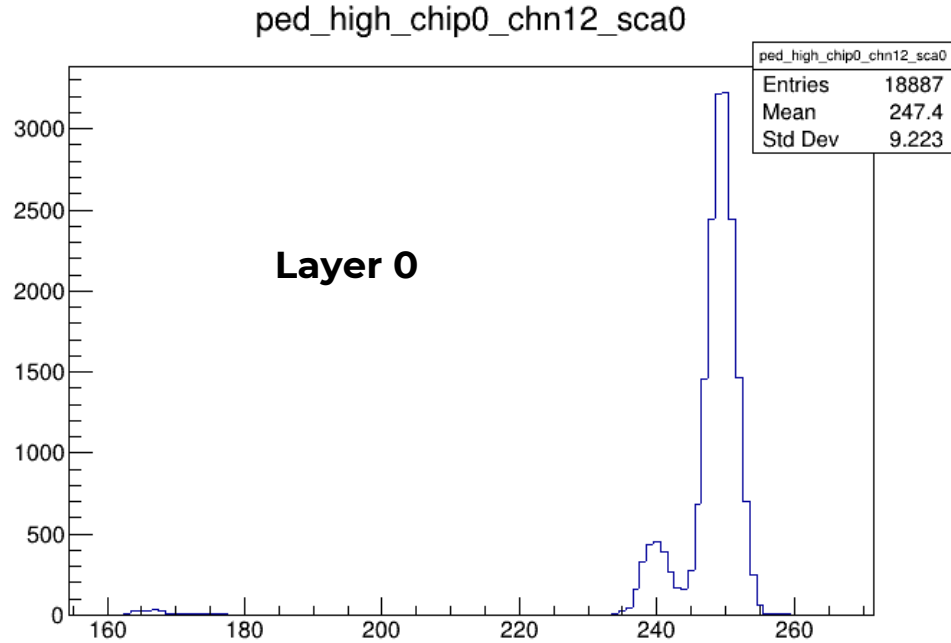

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► Selection

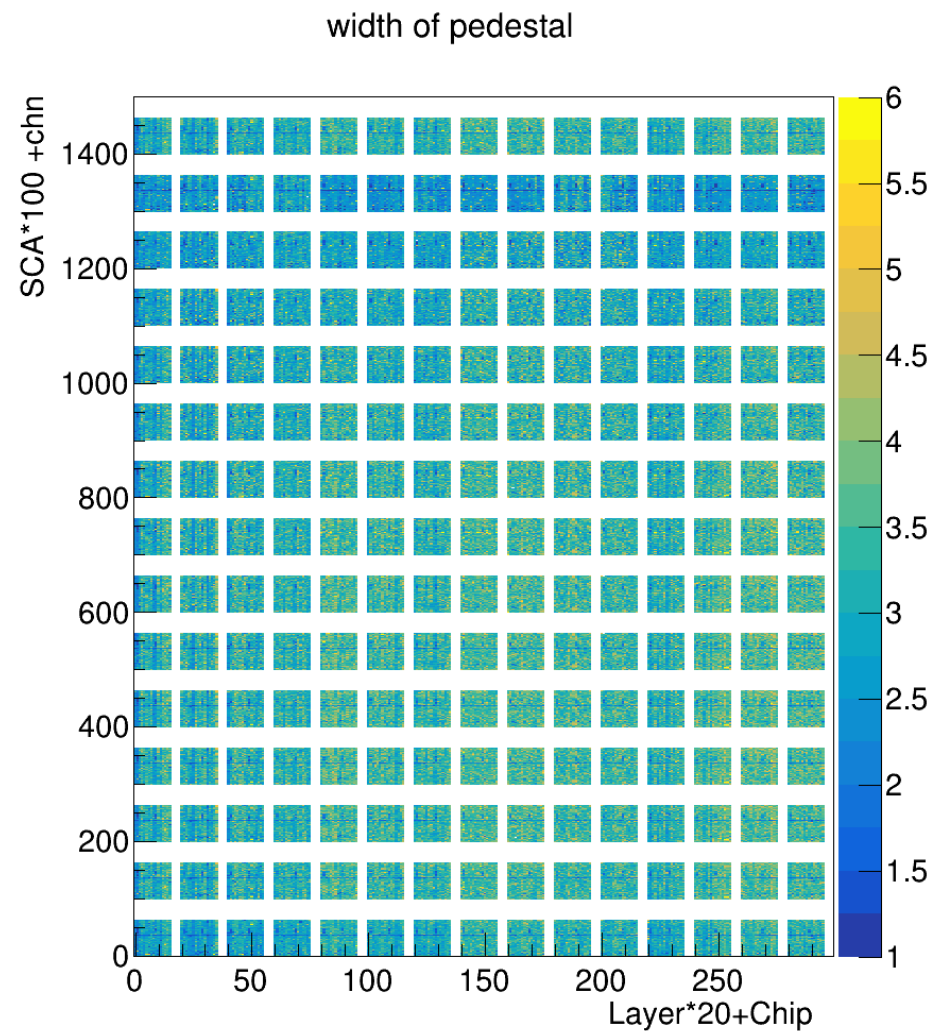
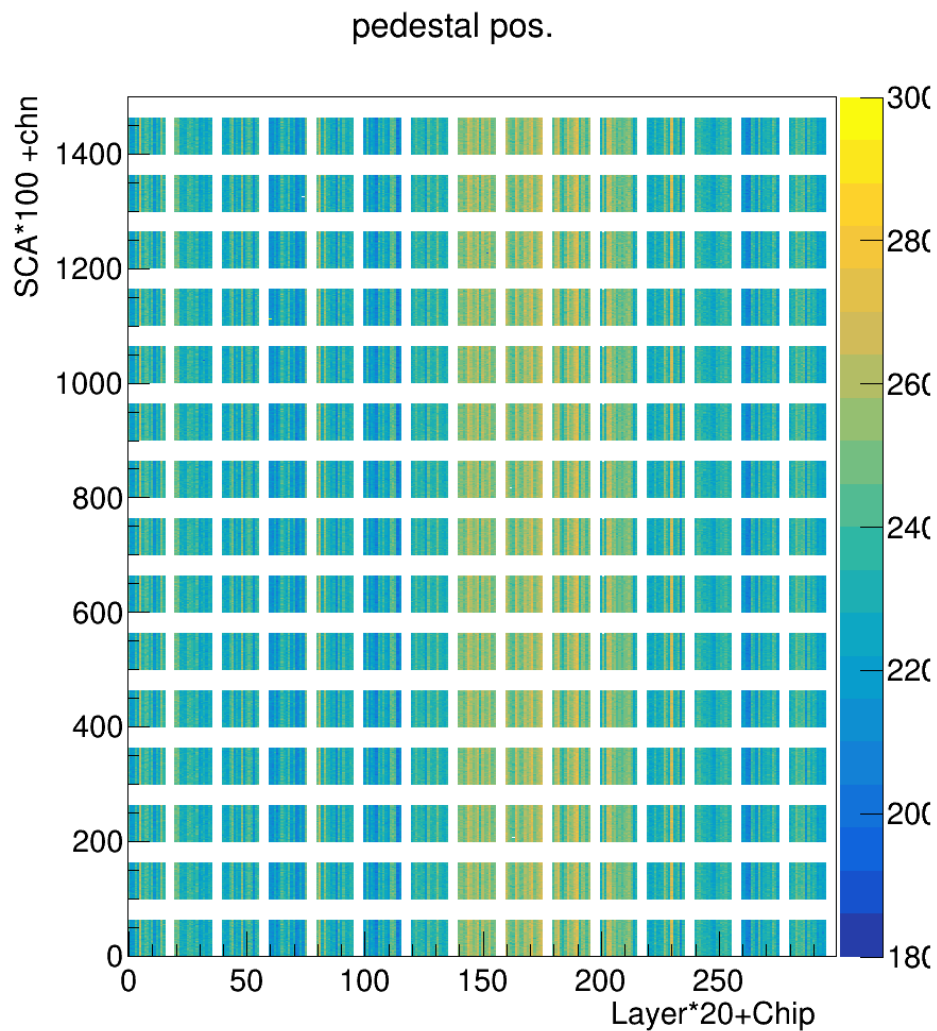
- 90 runs for MIPscan – > 3GeV MIPscan runs
- At least 10 layers in coincidence (+1 BCID) (coincidence in the same chip ID)
- Only store the charge if only 1 hit per chip
- Avoid noise sources: burst at bcid 0, burst at bcid 999.
- Avoid also last sca (prompt to be filled by retriggers...) → maybe too conservative

- ▶ Selection
- ▶ Perform a fit layer/chip/chn/sca wise
 - Gaussian, around the center of the largest peak



- ▶ Selection
- ▶ Perform a fit layer/chip/chn/sca wise
 - Gaussian, around the center of the largest peak
- ▶ Pedestal values stored in txt files
- ▶ I store 3 numbers per chn/sca:
 - Mean, error_mean_from_fit, width
 - If more than two peaks are found or the fit doesn't converge I store the average of mean and width (over the 15scas) and **error_mean_from_fit=-5**
 - If there is no enough statistics I store the average of mean and width (over the 15scas), and **error_mean_from_fit=-10**

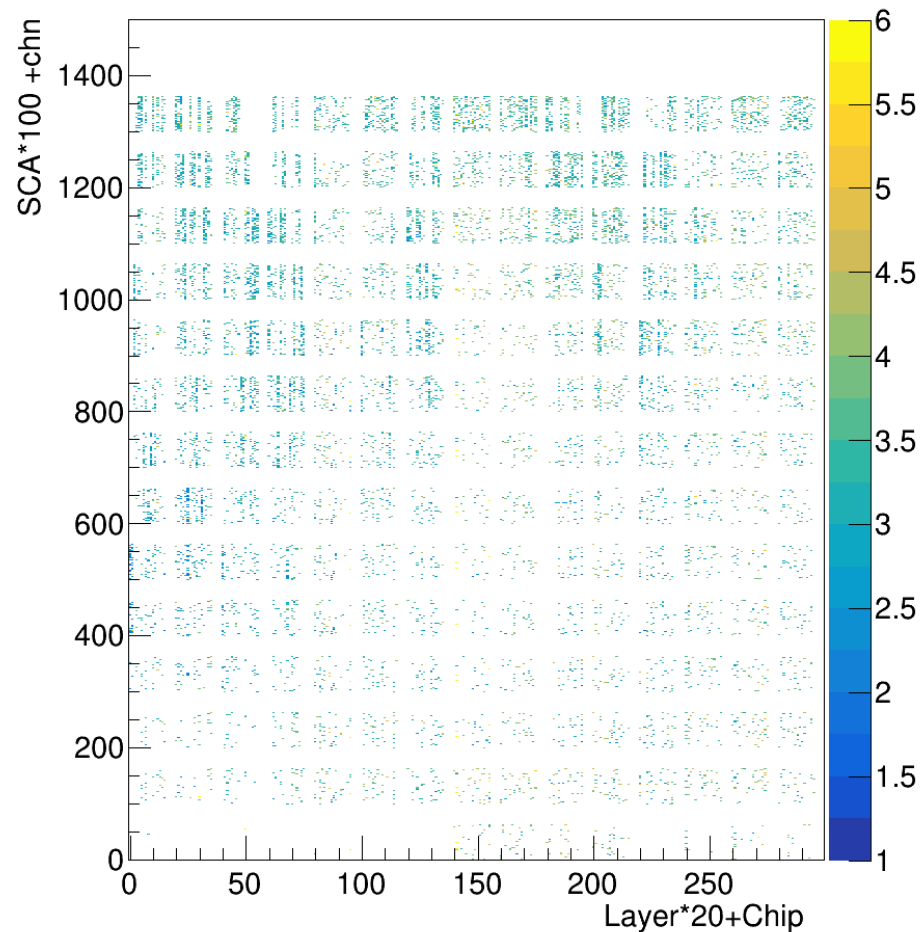
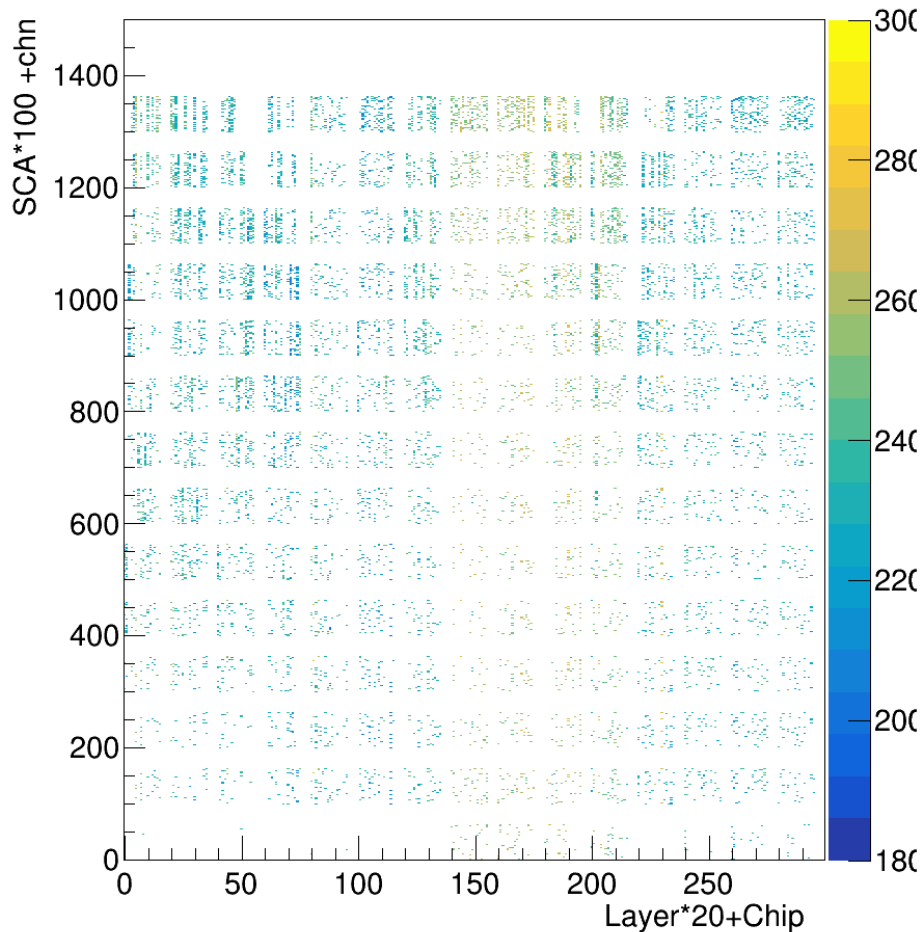
Pedestal (all scas, high-gain)



Pedestal (bad-fits, high-gain)

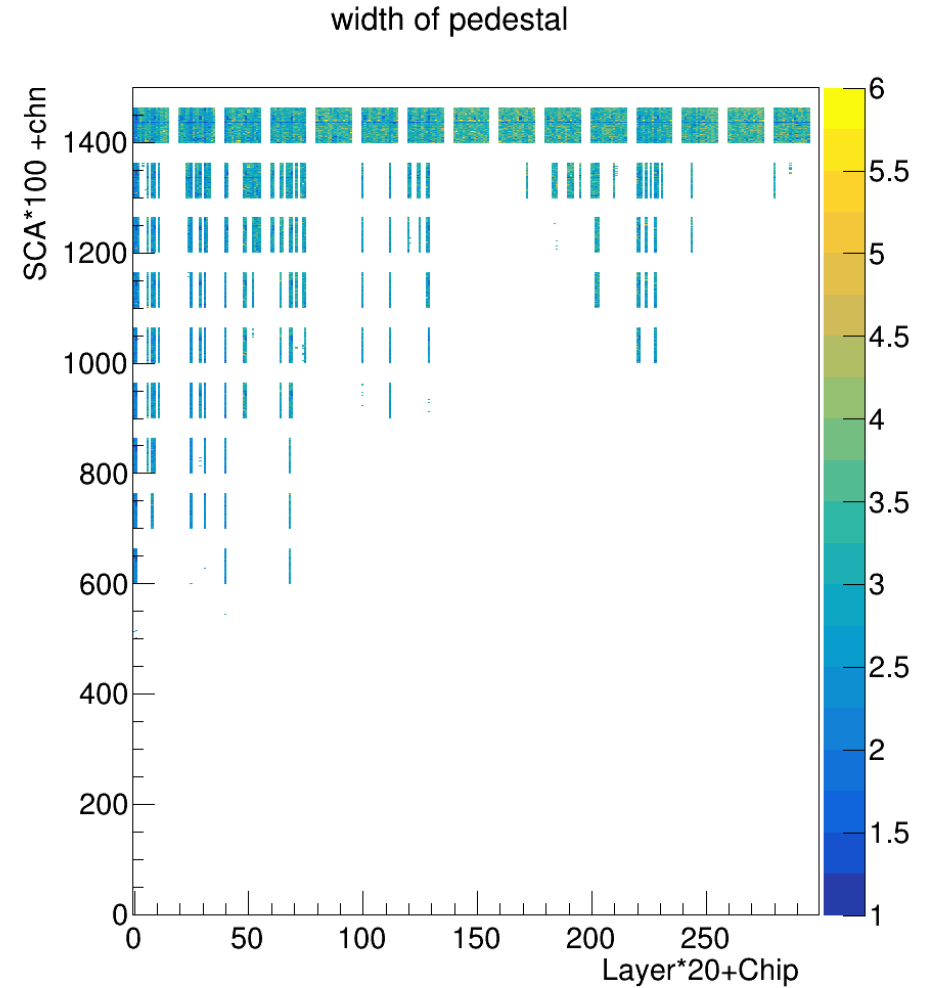
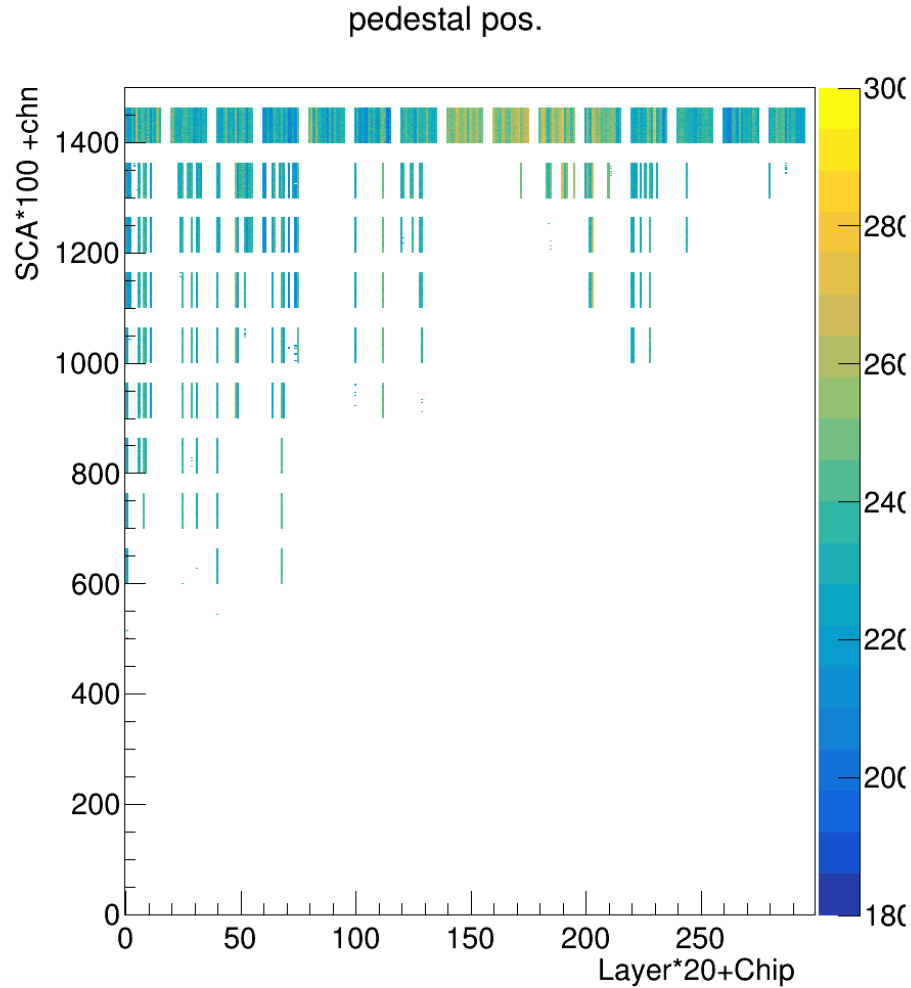
pedestal pos.

width of pedestal



4.8% of histograms

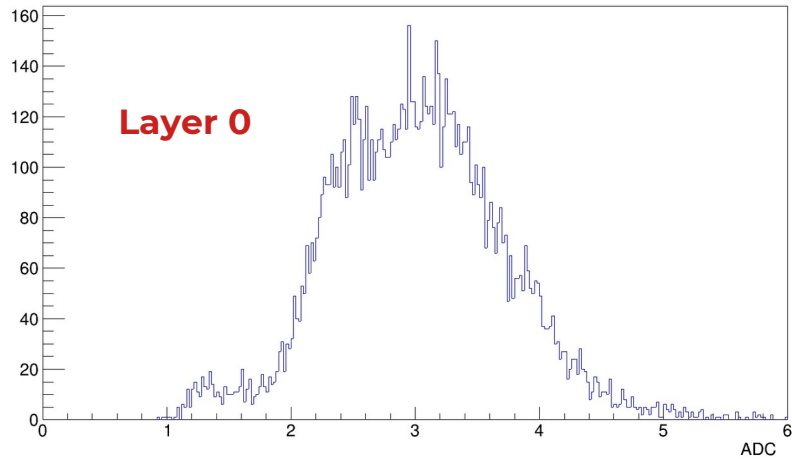
Pedestal (no stats, high-gain)



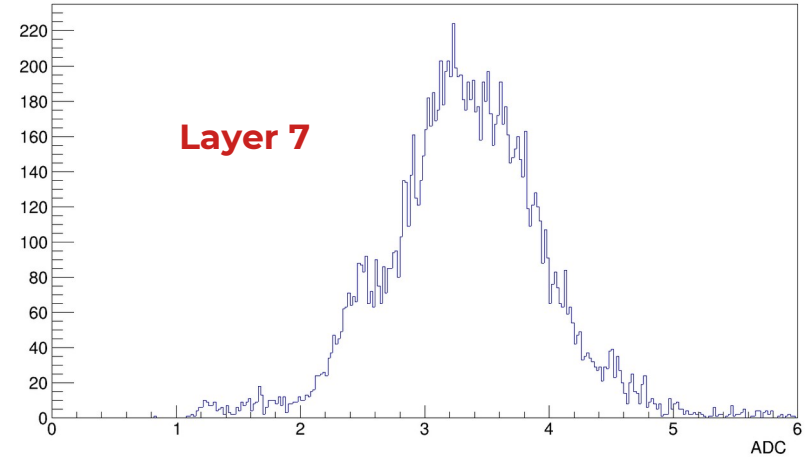
12% of pedestals but located in the last sca

Distributions of widths per layer

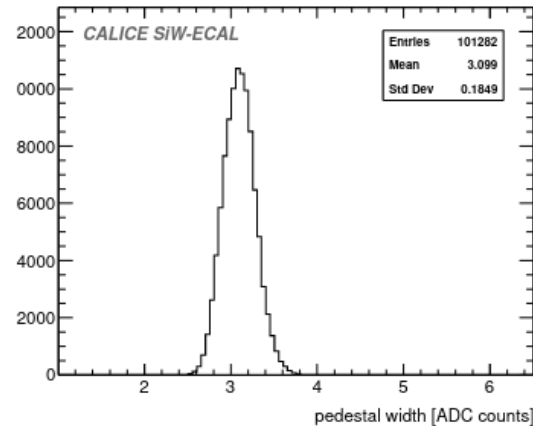
widths of pedestal



widths of pedestal

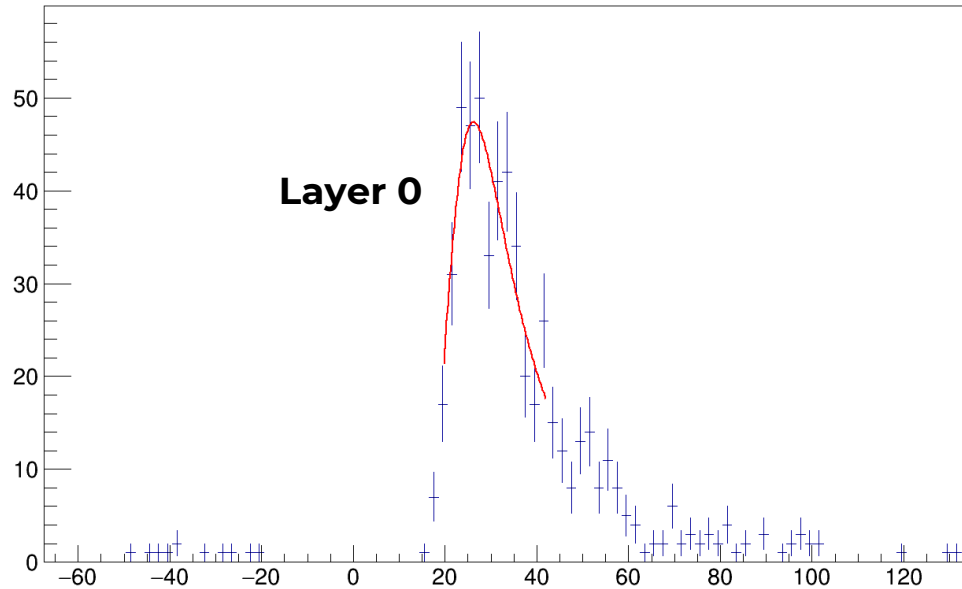


- ▶ Larger spread than at 2017
- ▶ Layer 7 has thicker wafer

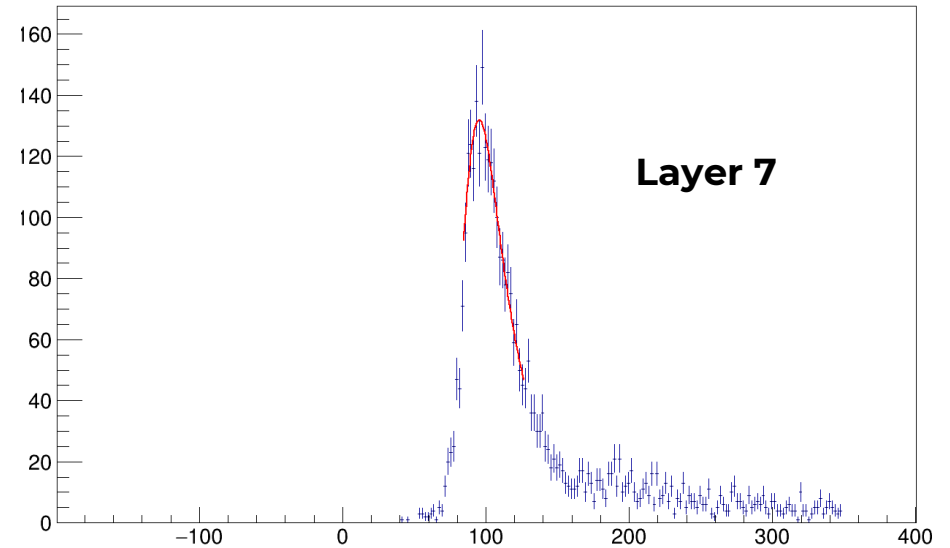


- ▶ Selection (same as pedestal)
- ▶ Perform a fit layer/chip/chn wise after pedestal subtraction (sca wise)
 - Langaus (landau convoluted with gaussian)

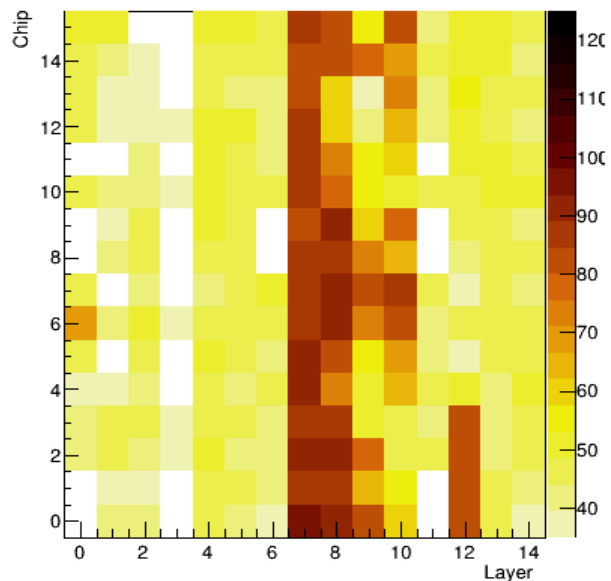
mip_high_layer0_chip0_chn27



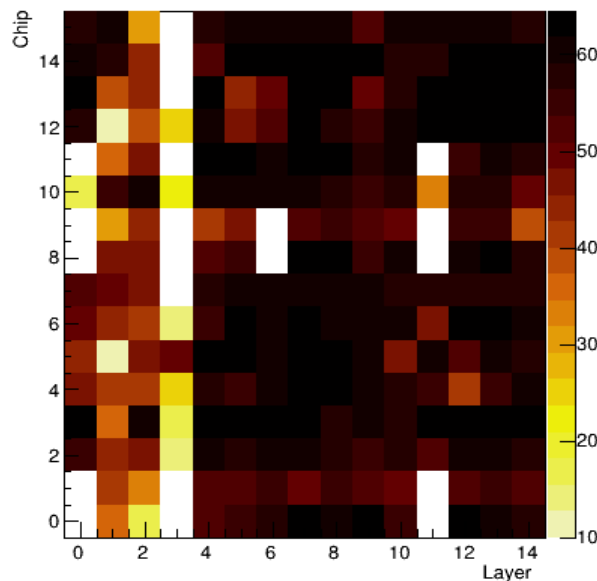
mip_high_layer7_chip0_chn0



average of MPVs



channels fitted



In general there are different noise conditions than in 2017
Higher HV?, more slabs, no power pulsing (nor big capacitor),
more density ...

- ▶ Larger noise and more difficult to perform the pedestal calibration and subtraction
- ▶ This causes that:
- ▶ Some layers have very low MIP values
 - Layer 0, layer 4, some chips in layer 11
- ▶ Layer 3 (FEV10, slab15) has almost no good hits...
 - Only noise? Desynchronized events ?
- ▶ Layers 9 and 10 are also weird
 - And these were supposed to be good ones...
 - FEV12 glued last year. What's different ?
 - Different equipment ?
 - Different glue/viscosity ?

Coherent noise source identification in multi channel analysis

<https://arxiv.org/pdf/1401.7095.pdf>

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Orsay, France

May 4, 2021

- ▶ “The goal is to identify and characterize dissociable noise sources in a multi channel systems. This method cannot separated noise sources which affect exactly the same set of channels. In this case, the noises sources are processed as a single source. We consider a system with N channels. “
- ▶ “Each channel \mathbf{k} is affected by an incoherent noise source \mathbf{I}_k and N_c coherent noise sources ($\mathbf{C1}_k, \mathbf{C2}_k, \dots, \mathbf{CN}_k$). We assume that all noise source distributions are Gaussian and independant.”

$$\sigma_i^2 = \sigma_{I_i}^2 + \sum_{j=1}^{N_c} \sigma_{C_i^j}^2 \quad (1)$$

The covariance matrix element from the two channels i and k is expressed by:

$$\text{cov}(i, k) = \delta_{ik} \sigma_{I_i} \sigma_{I_k} + \sum_{j=1}^{N_c} \sigma_{C_i^j} \sigma_{C_k^j} \quad (2)$$

where:

$$\delta_{ik} = \begin{cases} 1 & \text{if } i = k \\ 0 & \text{if } i \neq k \end{cases} \quad (3)$$

The covariance matrix element can also be determined from the data:

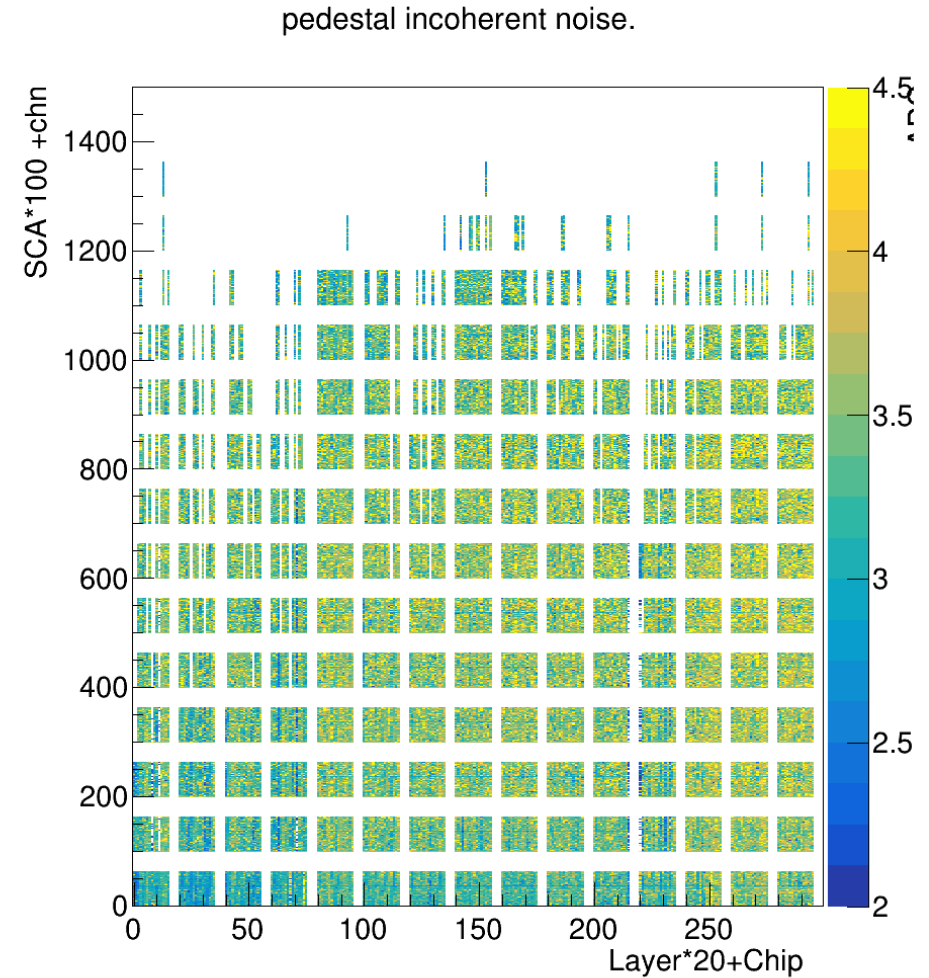
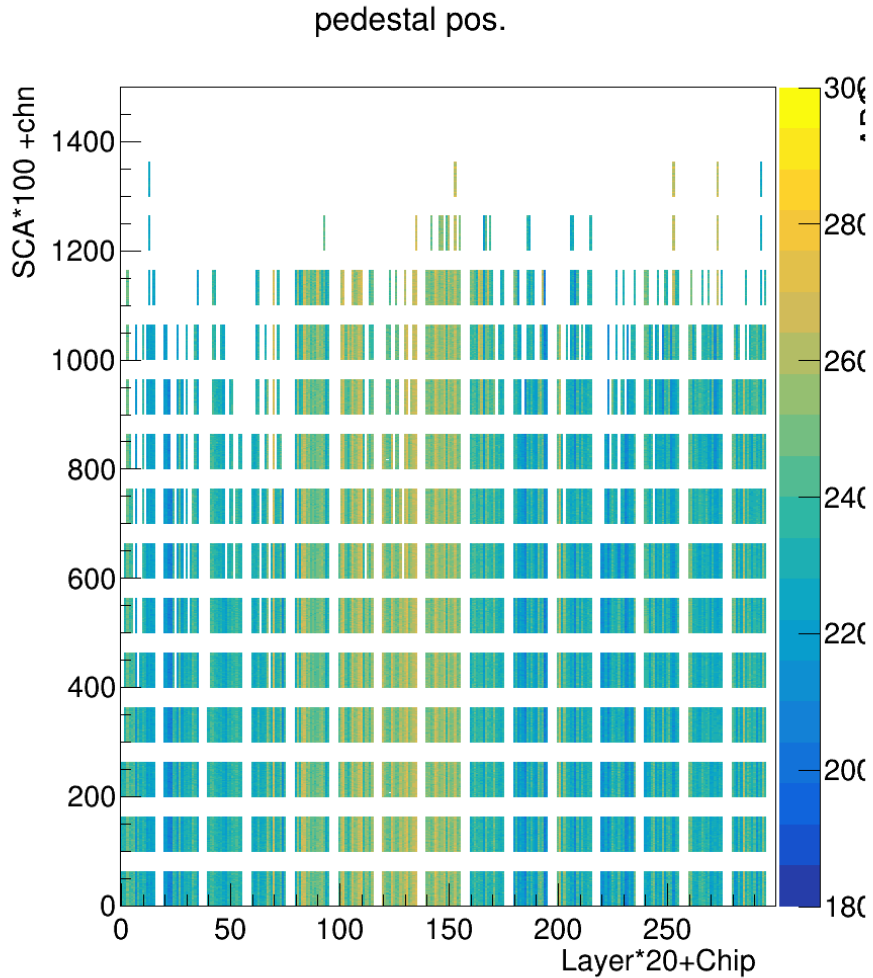
$$\text{cov}_{Data}(i, k) = \frac{\sum_{n=1}^{N_{event}} (A_i(n) - \mu_{A_i})(A_k(n) - \mu_{A_k})}{N_{event}} \quad (4)$$

Measured amplitude if no hit

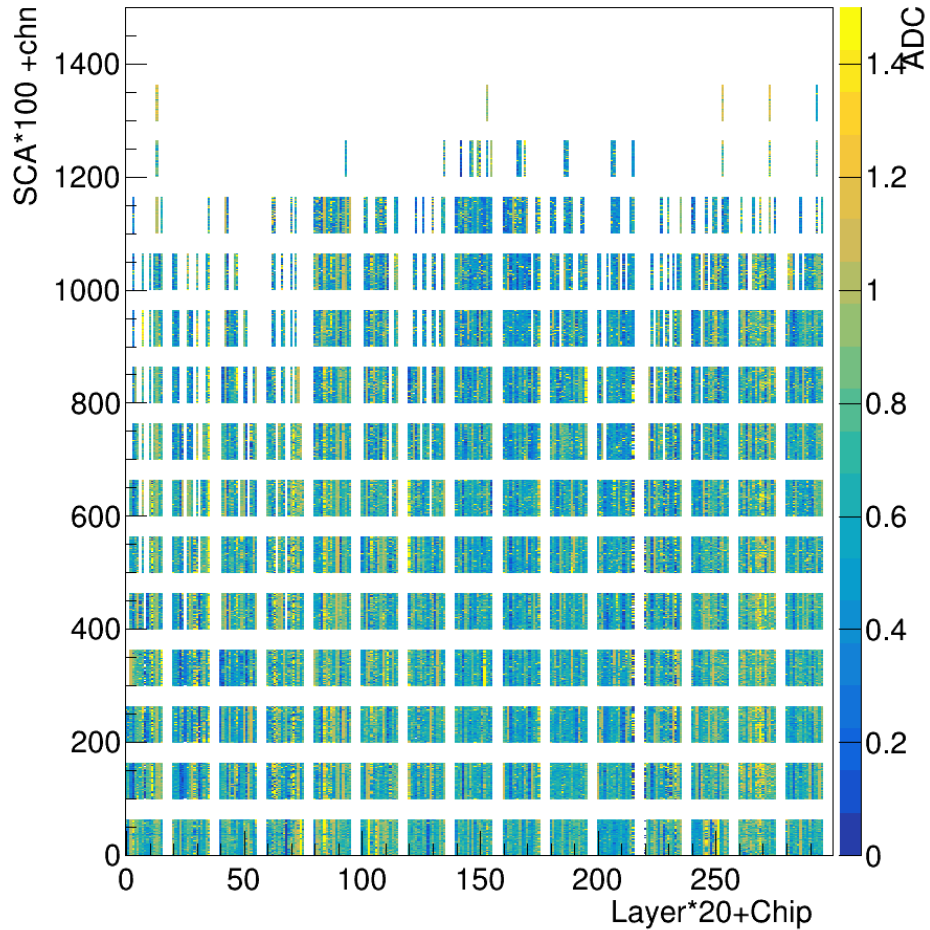
Pedestal position → calculated as simple histogram Mean

- ▶ We use the same selection as described in page 2
- ▶ The average pedestal is calculated on the fly
 - No gaussian fit is performed
- ▶ Following same recipe than in the CALICE note, we get the convergence with 2 coherent noises

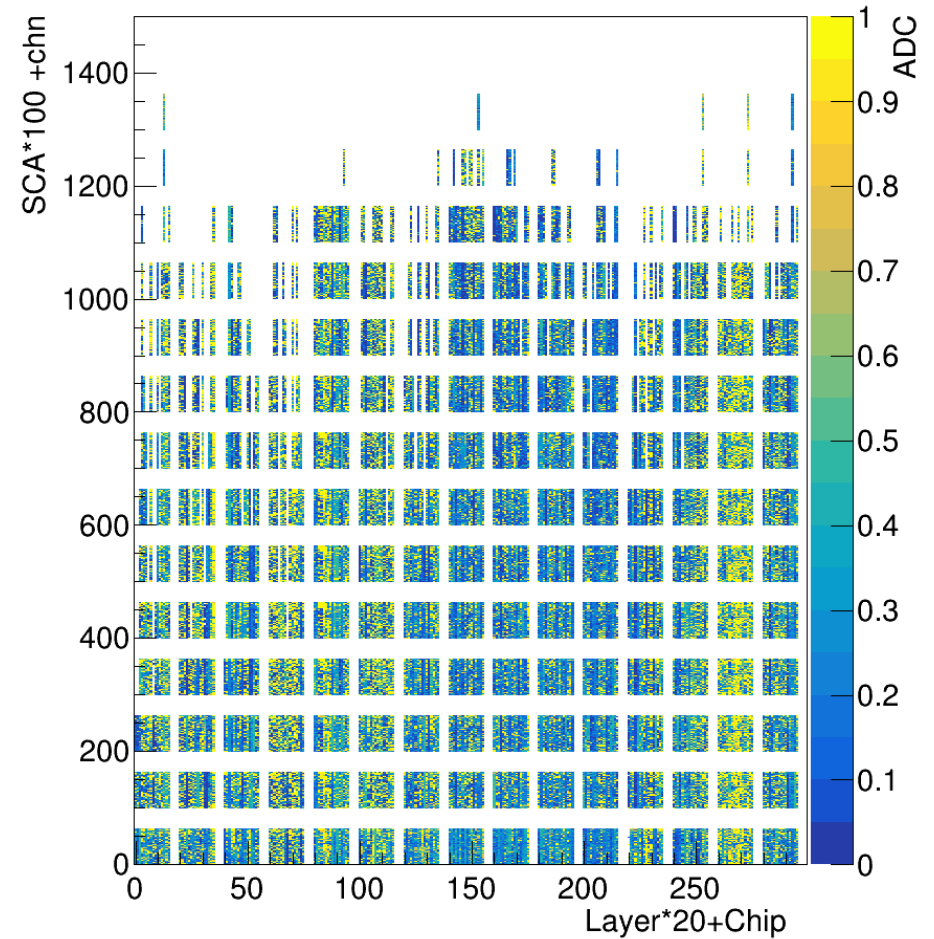
Pedestal position and incoherent noise

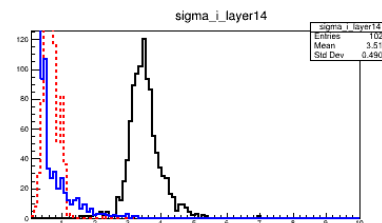
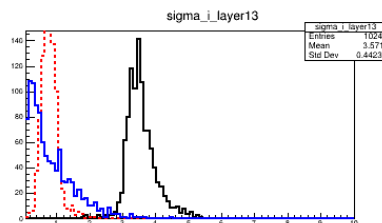
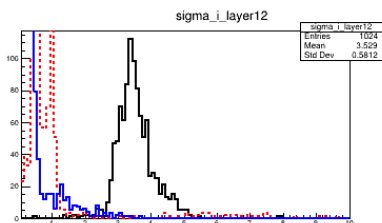
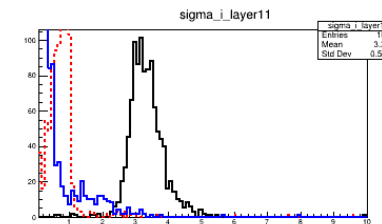
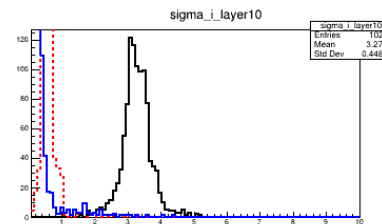
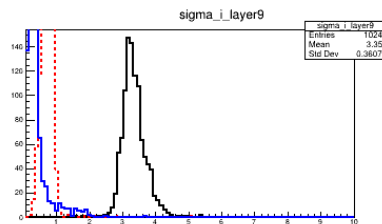
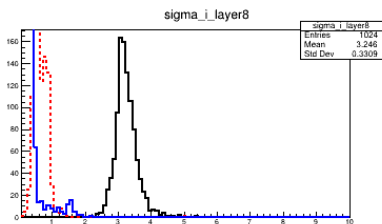
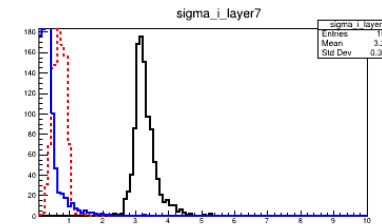
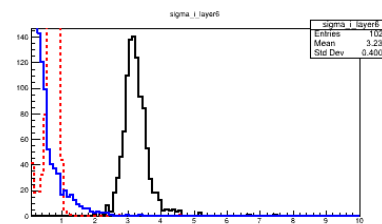
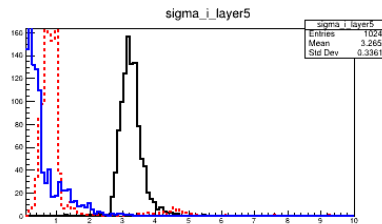
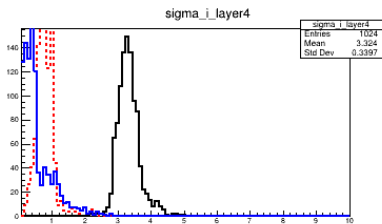
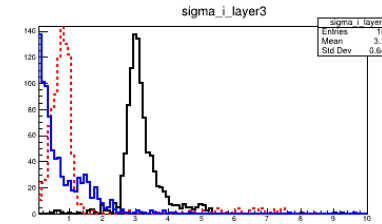
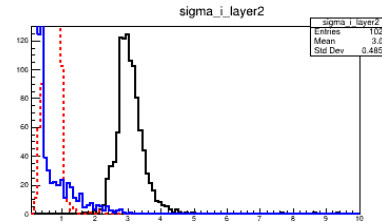
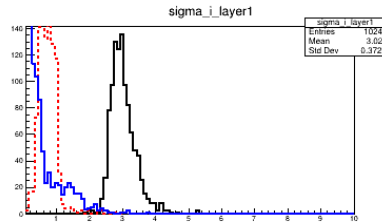
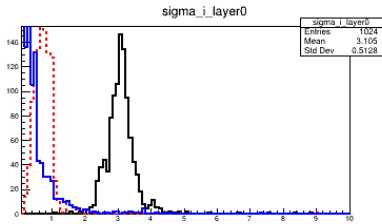


pedestal coherent-1 noise



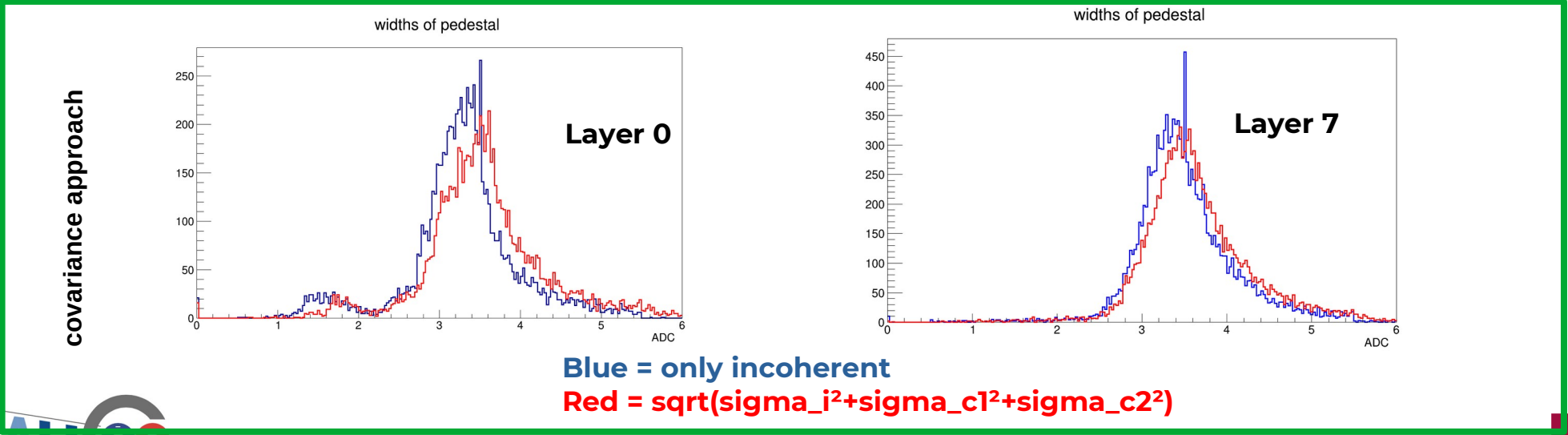
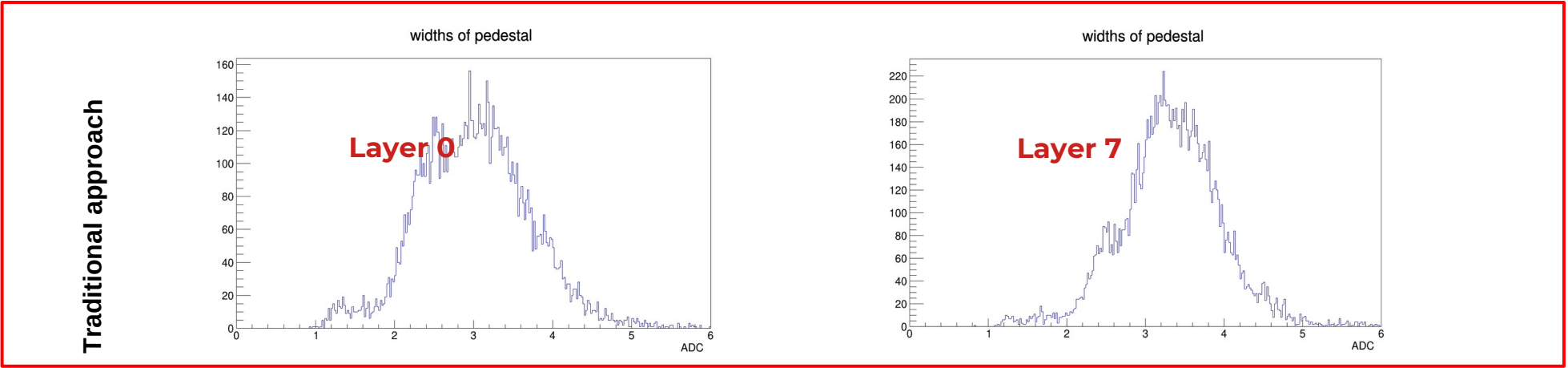
pedestal coherent-2 noise





black = only incoherent
red = c1
blue = c2

Distributions of widths per layer

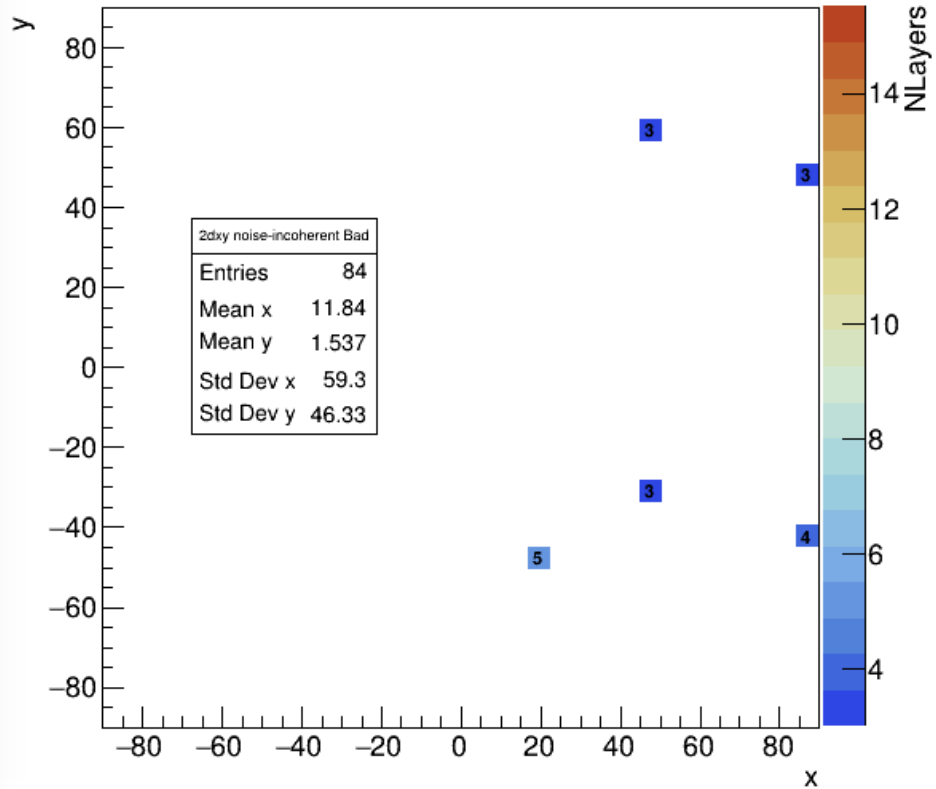


Noise "geometry" (SCA0)

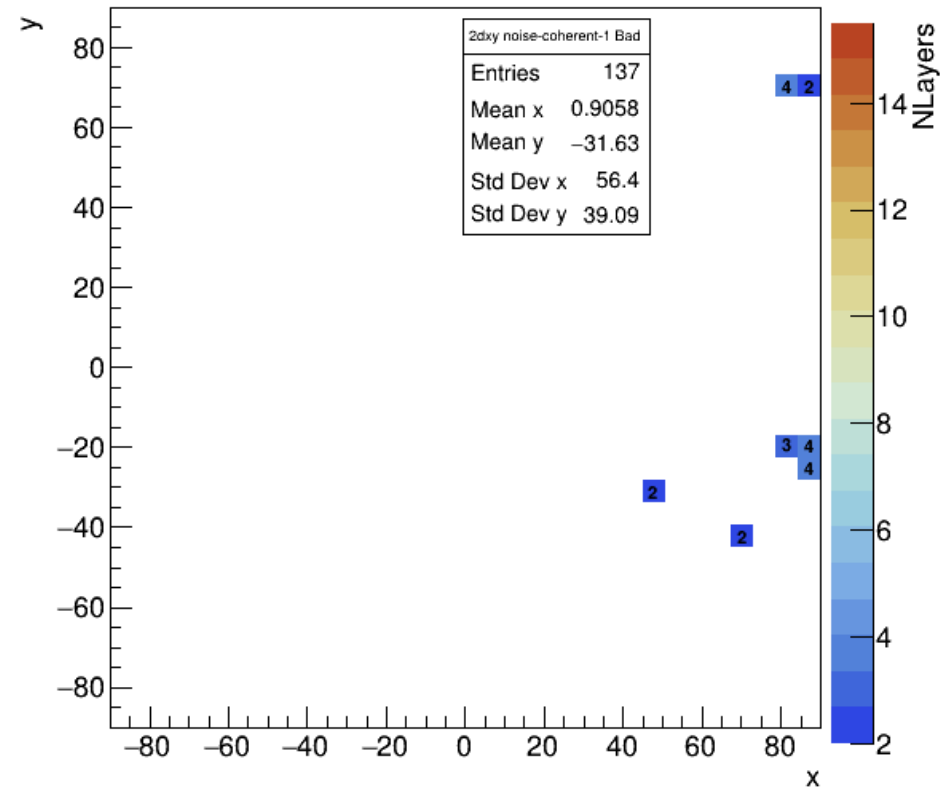
File Edit View Options Tools

Help

Layers with $\sigma_i > 5\text{ADC}$



Layers with $\sigma_{c1} > 2.5\text{ADC}$

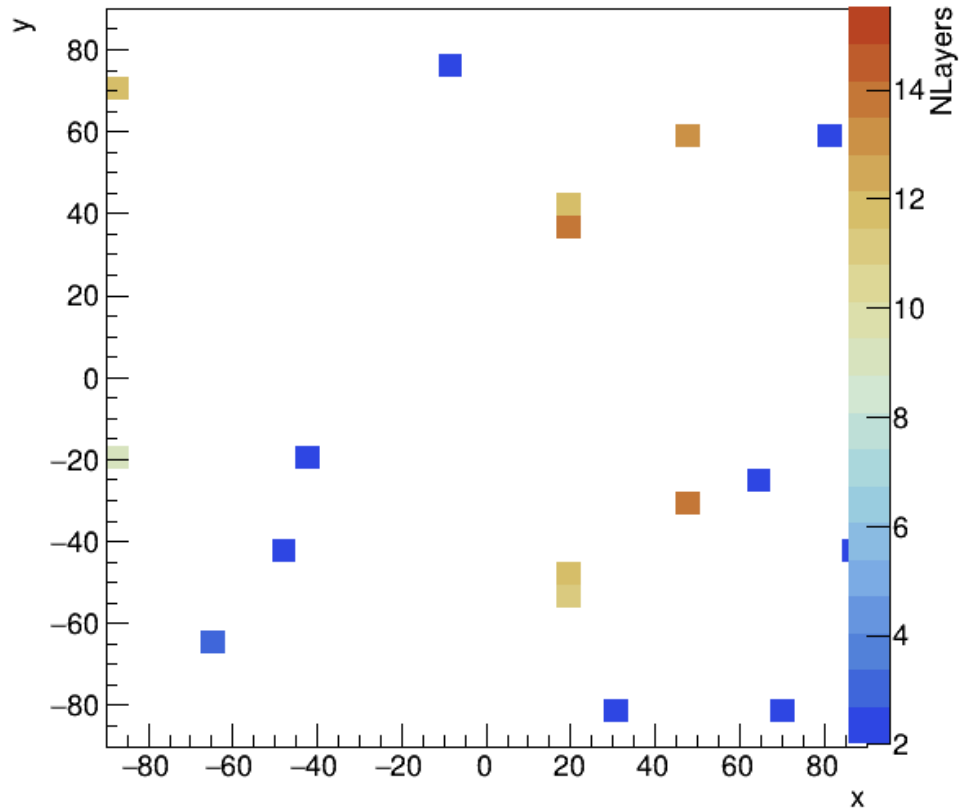


Noise "geometry" (SCA1)

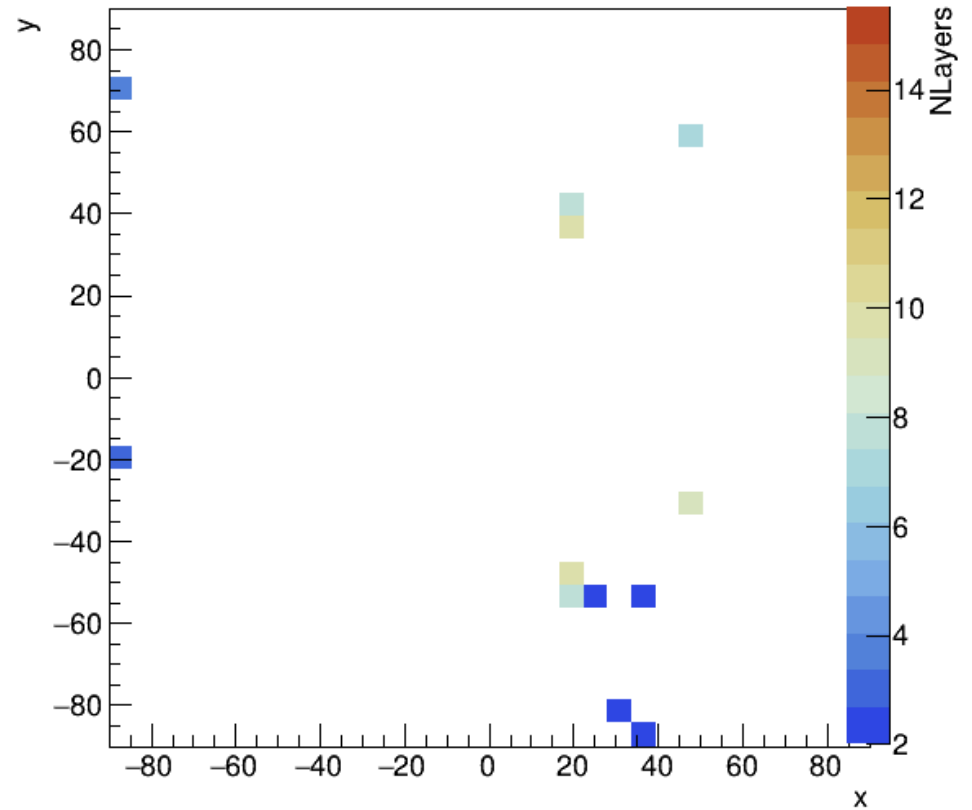
File Edit View Options Tools

Help

Layers with $\sigma_i > 5\text{ADC}$



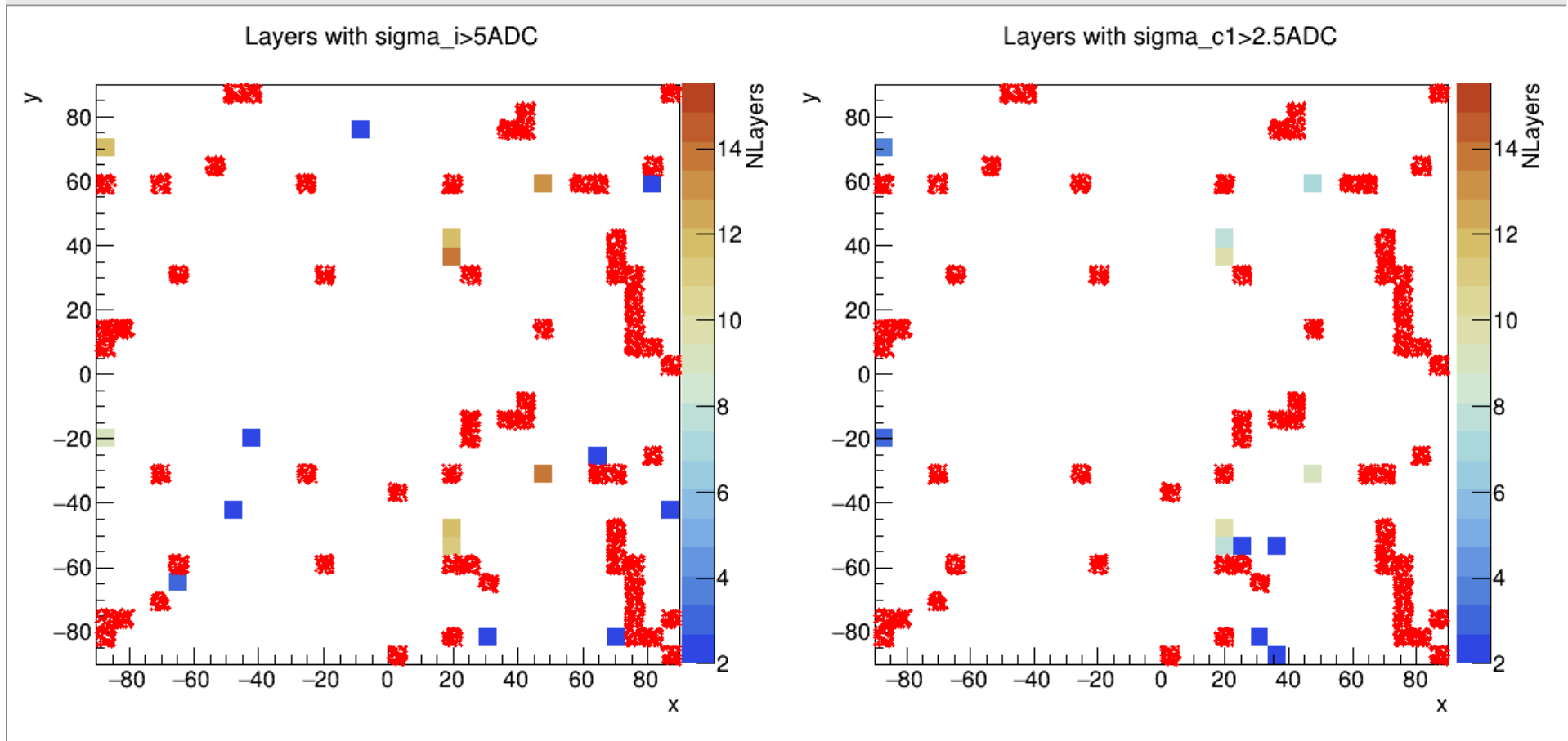
Layers with $\sigma_{c1} > 2.5\text{ADC}$



Noise "geometry" (SCA1) + default masking

File Edit View Options Tools

Help



- ▶ Gradual optimization of the calibration
 - For example not being so much conservative in the selection (allowing sca=14, more than 1 hit etc, bcid+-2 ?)
- ▶ Repeat the MIP & S/N analysis using the new pedestal calculations
- ▶ Upload new calibration files to the eos
- ▶ Low vs High gain comparisons